GC3M0120090D

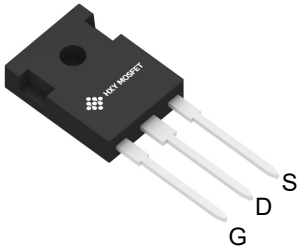
SiC Power MOSFET N-Channel Enhancement Mode

Features

- 3rd generation SiC MOSFET technology
- Optimized package with separate driver source pin
- High blocking voltage with low on-resistance
- High-speed switching with low capacitances
- Fast intrinsic diode with low reverse recovery (Q_{rr})
- Halogen free, RoHS compliant

Benefits

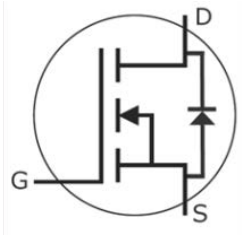
- Reduce switching losses and minimize gate ringing
- Higher system efficiency
- Reduce cooling requirements
- Increase power density
- Increase system switching frequency



TO-247

Applications

- Renewable energy
- EV battery chargers
- High voltage DC/DC converters
- Switch Mode Power Supplies



Ordering Part Number	Package	Packing
GC3M0120090D	TO-247	Tube

Maximum Ratings (T_C = 25 ˚C unless otherwise specified)

Symbol	Parameter	Value	Unit	Test Conditions	Note
V_{DSmax}	Drain - Source Voltage	900	V	V_{GS} = 0 V, I_D = 100 µA	
V_{GSmax}	Gate - Source Voltage (dynamic)	-8/+19	V	AC (f >1 Hz)	Note: 1
V_{GSop}	Gate - Source Voltage (static)	-4/+15	V	Static	Note: 2
I_D	Continuous Drain Current	23	A	V_{GS} = 15 V, T_C = 25˚C	Fig. 19
		15		V_{GS} = 15 V, T_C = 100˚C	
$I_{D(pulse)}$	Pulsed Drain Current	50	A	Pulse width t_P limited by T_{jmax}	Fig. 22
P_D	Power Dissipation	97	W	T_C=25˚C, T_J = 150 ˚C	Fig. 20
T_J , T_{stg}	Operating Junction and Storage Temperature	-55 to +150	˚C		
T_L	Solder Temperature	260	˚C	1.6mm (0.063”) from case for 10s	
M_d	Mounting Torque	1 8.8	Nm lbf-in	M3 or 6-32 screw	

Electrical Characteristics (T_C = 25˚C unless otherwise specified)

Symbol	Parameter	Min.	Typ.	Max.	Unit	Test Conditions	Note
$V_{(BR)DSS}$	Drain-Source Breakdown Voltage	900			V	V_{GS} = 0 V, I_D = 100 µA	
$V_{GS(th)}$	Gate Threshold Voltage	1.8	2.1	3.5	V	V_{DS} = V_{GS}, I_D = 3 mA	Fig. 11
			1.6		V	V_{DS} = V_{GS}, I_D = 3 mA, T_J = 150ºC	
I_{DSS}	Zero Gate Voltage Drain Current		1	100	µA	V_{DS} = 900 V, V_{GS} = 0 V	
I_{GSS}	Gate-Source Leakage Current		10	250	nA	V_{GS} = 15 V, V_{DS} = 0 V	
$R_{DS(on)}$	Drain-Source On-State Resistance		120	155	mΩ	V_{GS} = 15 V, I_D = 15 A	Fig. 4, 5, 6
			170			V_{GS} = 15 V, I_D = 15 A, T_J = 150ºC	
g_{fs}	Transconductance		8.9		S	V_{DS}= 20 V, I_{DS}= 15 A	Fig. 7
			7.1			V_{DS}= 20 V, I_{DS}= 15 A, T_J = 150ºC	
C_{iss}	Input Capacitance		414		pF	V_{GS} = 0 V, V_{DS} = 600 V f = 1 MHz V_{AC} = 25 mV	Fig. 17, 18
C_{oss}	Output Capacitance		48				
C_{rss}	Reverse Transfer Capacitance		3				
E_{oss}	C_{oss} Stored Energy		10.6		µJ		Fig. 16
E_{ON}	Turn-On Switching Energy (Body Diode FWD)		176		µJ	V_{DS} = 400 V, V_{GS} = -4 V/15 V, I_D = 15 A, $R_{G(ext)}$ = 2.5Ω, L= 99 µH, T_J = 150ºC	Fig. 26, 29
E_{OFF}	Turn Off Switching Energy (Body Diode FWD)		36				
$t_{d(on)}$	Turn-On Delay Time		6		ns	V_{DD} = 400 V, V_{GS} = -4 V/15 V I_D = 15 A, $R_{G(ext)}$ = 2.5Ω, Timing relative to V_{DS} Inductive load	Fig. 27, 29
t_r	Rise Time		32				
$t_{d(off)}$	Turn-Off Delay Time		14				
t_f	Fall Time		7				
$R_{G(int)}$	Internal Gate Resistance		13		Ω	f = 1 MHz, V_{AC} = 25 mV	
Q_{gs}	Gate to Source Charge		5		nC	V_{DS} = 400 V, V_{GS}=-4V/15V I_D = 15 A Per IEC60747-8-4 pg 21	Fig. 12
Q_{gd}	Gate to Drain Charge		8				
Q_g	Total Gate Charge		21				

Reverse Diode Characteristics (T_C = 25˚C unless otherwise specified)

Symbol	Parameter	Typ.	Max.	Unit	Test Conditions	Note
V_{SD}	Diode Forward Voltage	4.8		V	V_{GS} = -4 V, I_{SD} = 7.5 A	Fig. 8, 9, 10
		4.4		V	V_{GS} = -4 V, I_{SD} = 7.5 A, T_J = 150 °C	
I_S	Continuous Diode Forward Current		15	A	V_{GS} = -4 V	Note 1
$I_{S,\ pulse}$	Diode pulse Current		50	A	V_{GS} = -4 V, pulse width t_P limited by T_{jmax}	Note 1
t_{rr}	Reverse Recover time	28		ns	V_{GS} = -4 V, I_{SD} = 15 A, V_R = 400V dif/dt = 600 A/µs, T_J = 150 °C	Note 1
Q_{rr}	Reverse Recovery Charge	127		nC		
I_{rrm}	Peak Reverse Recovery Current	6		A		

Thermal Characteristics

Symbol	Parameter	Max.	Unit	Test Conditions	Note
$R_{\theta JC}$	Thermal Resistance from Junction to Case	1.3	°C/W		Fig. 21
$R_{\theta JA}$	Thermal Resistance From Junction to Ambient	40			

Typical Performance

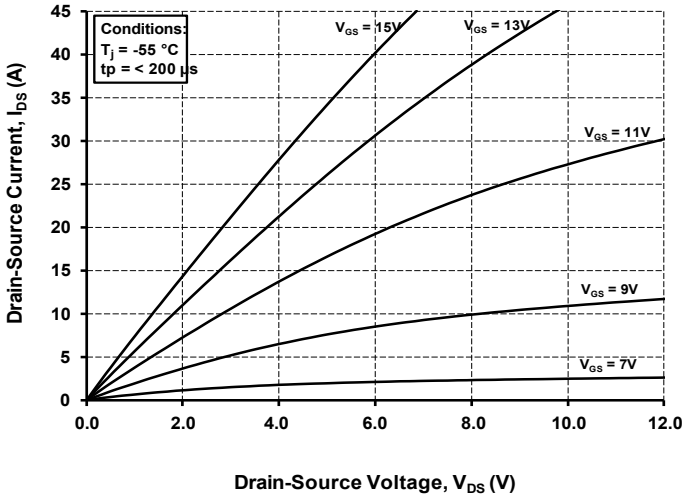


Figure 1. Output Characteristics T_J = -55 ºC

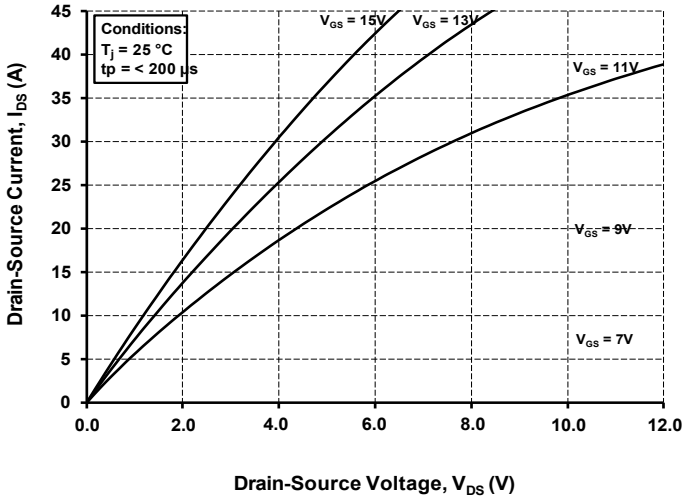


Figure 2. Output Characteristics T_J = 25 ºC

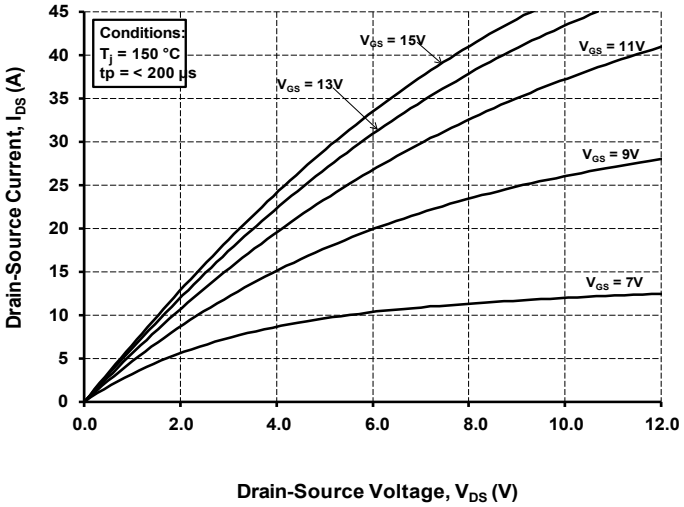


Figure 3. Output Characteristics T_J = 150 ºC

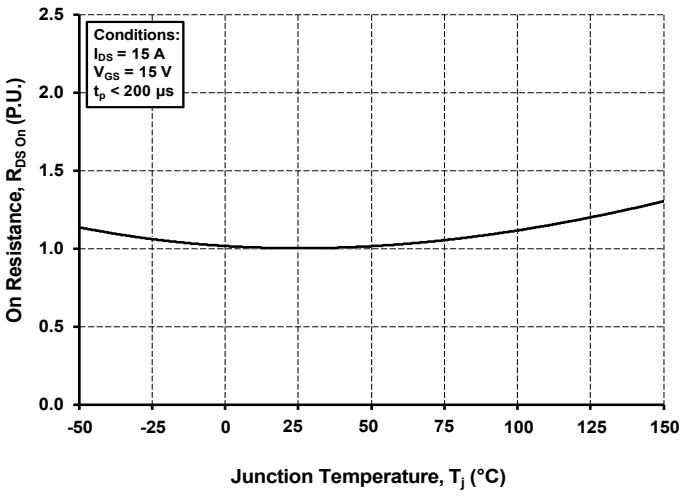


Figure 4. Normalized On-Resistance vs. Temperature

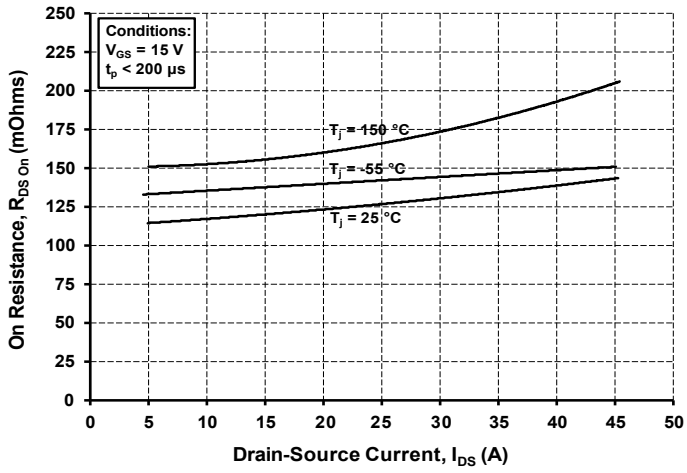


Figure 5. On-Resistance vs. Drain Current For Various Temperatures

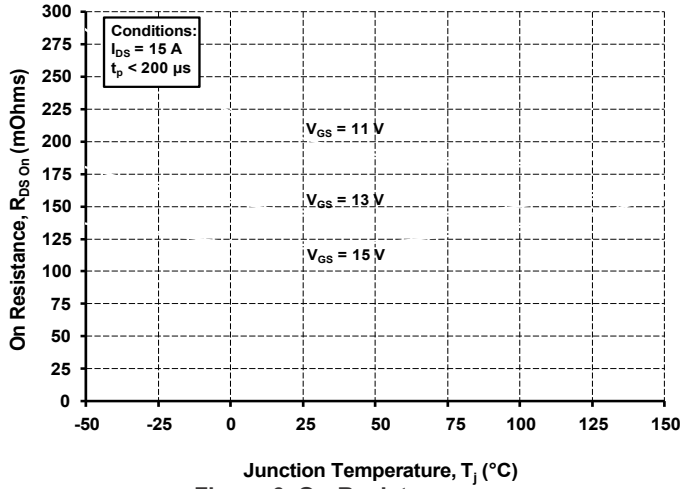


Figure 6. On-Resistance vs. Temperature For Various Gate Voltage

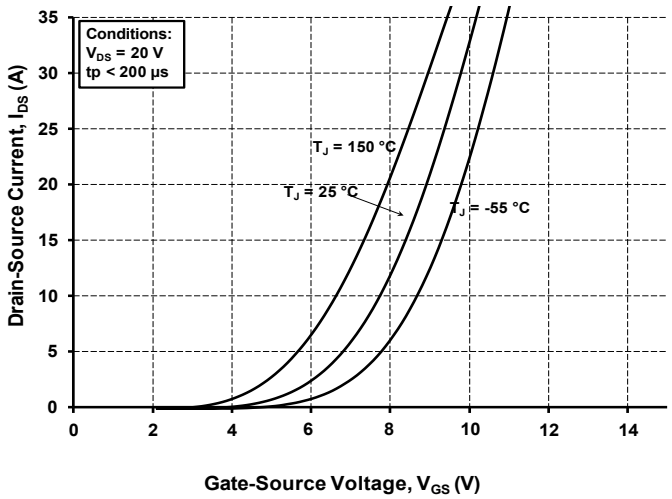


Figure 7. Transfer Characteristic for Various Junction Temperatures

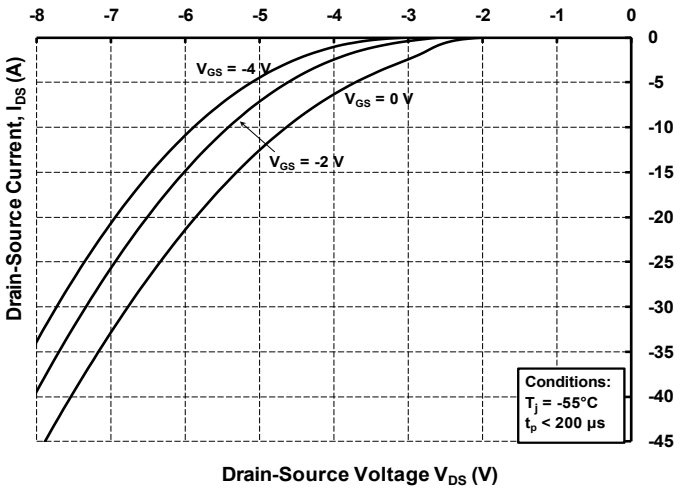


Figure 8. Body Diode Characteristic at -55 ºC

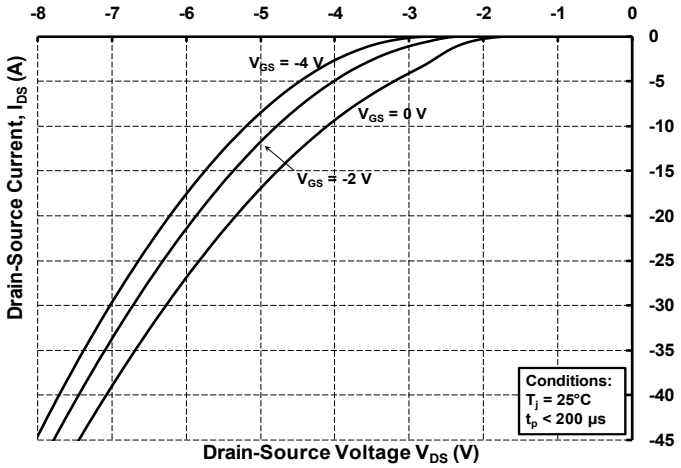


Figure 9. Body Diode Characteristic at

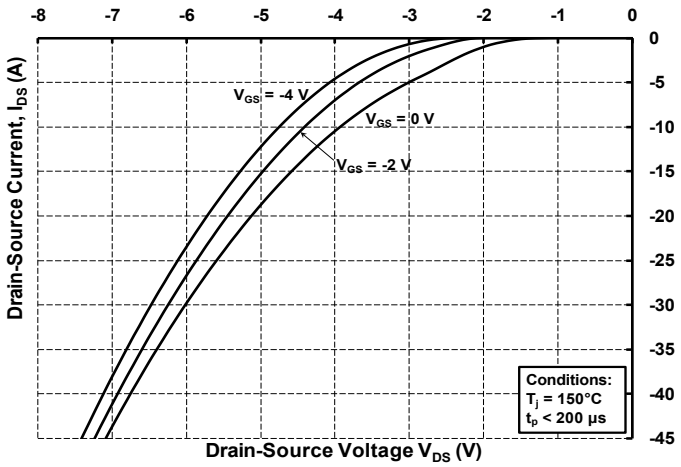


Figure 10. Body Diode Characteristic at

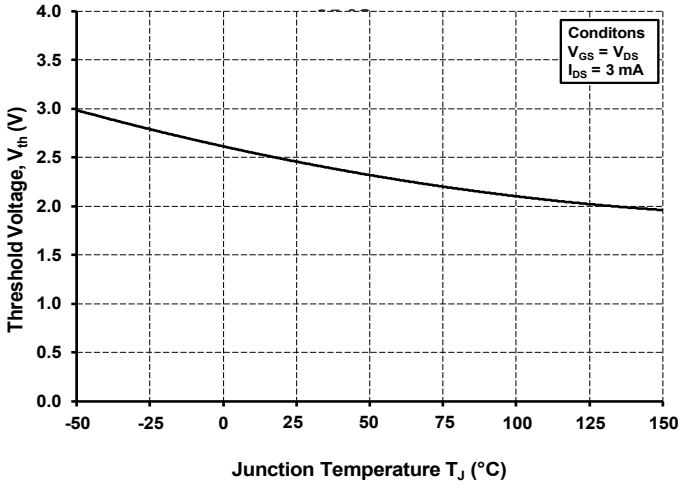


Figure 11. Threshold Voltage vs. Temperature

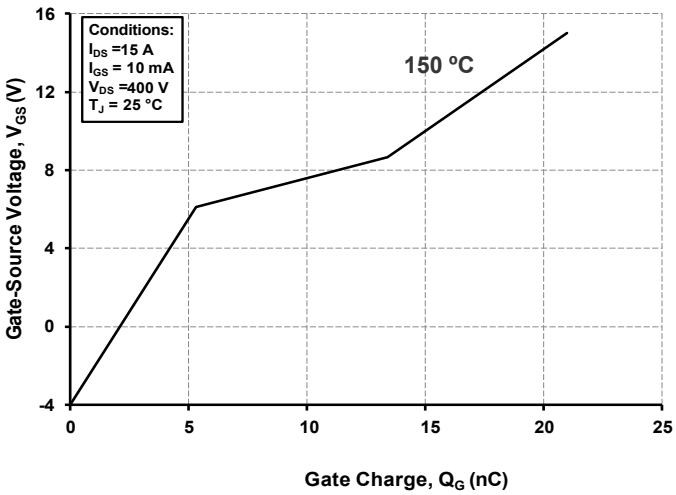


Figure 12. Gate Charge Characteristics

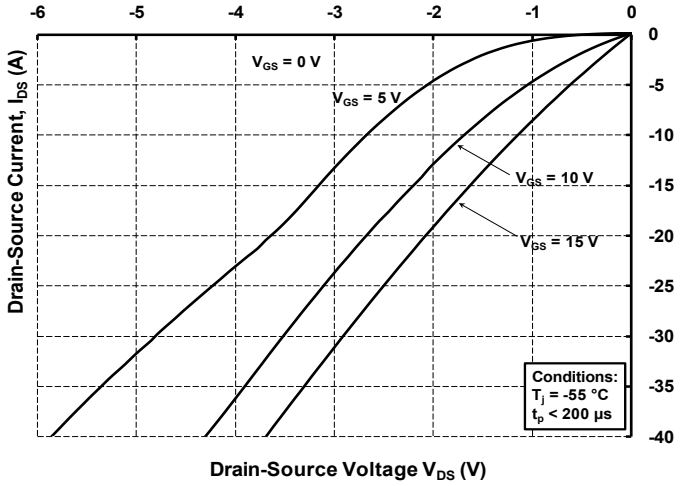


Figure 13. 3rd Quadrant Characteristic at -55 ºC

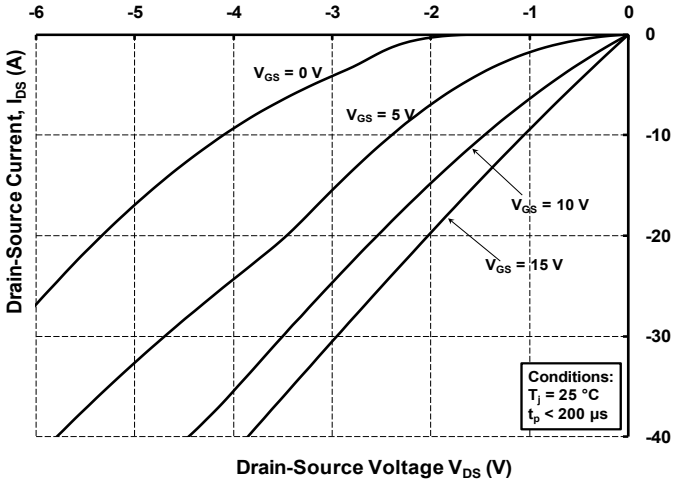


Figure 14. 3rd Quadrant Characteristic at 25 ºC

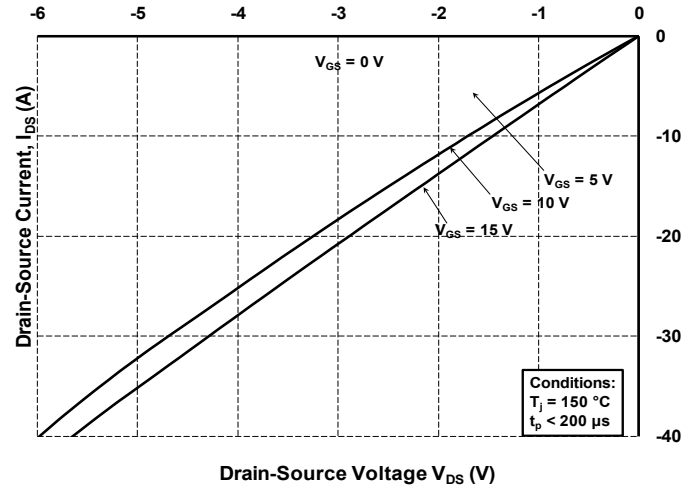


Figure 15. 3rd Quadrant Characteristic at 150 ºC

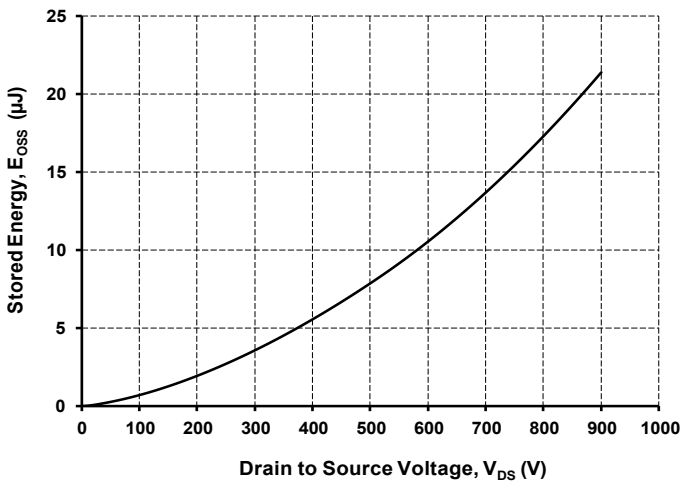


Figure 16. Output Capacitor Stored Energy

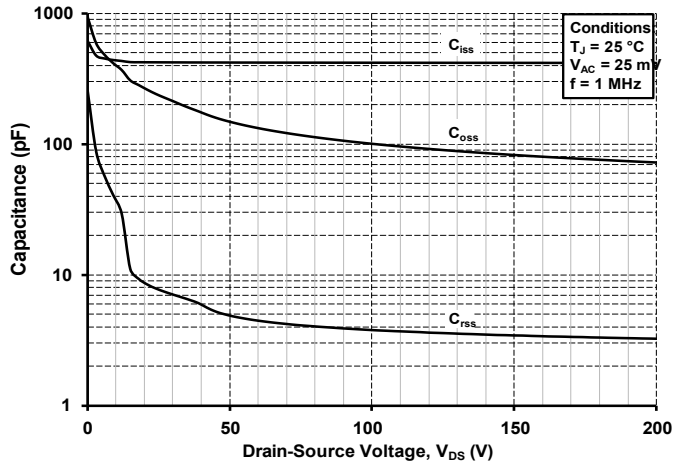


Figure 17. Capacitances vs. Drain-Source Voltage (0 - 200V)

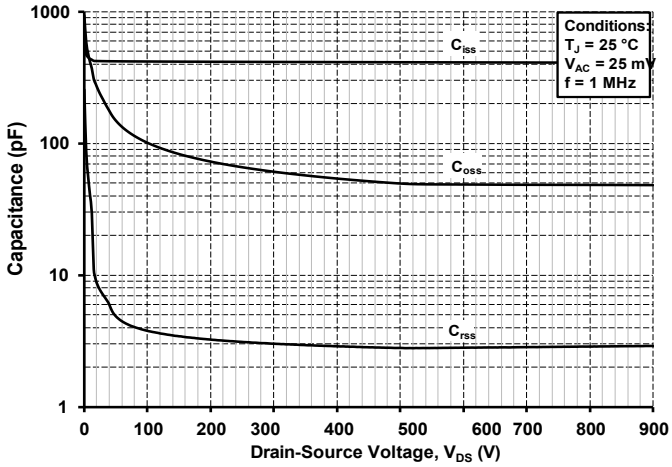


Figure 18. Capacitances vs. Drain-Source Voltage (0 - 900V)

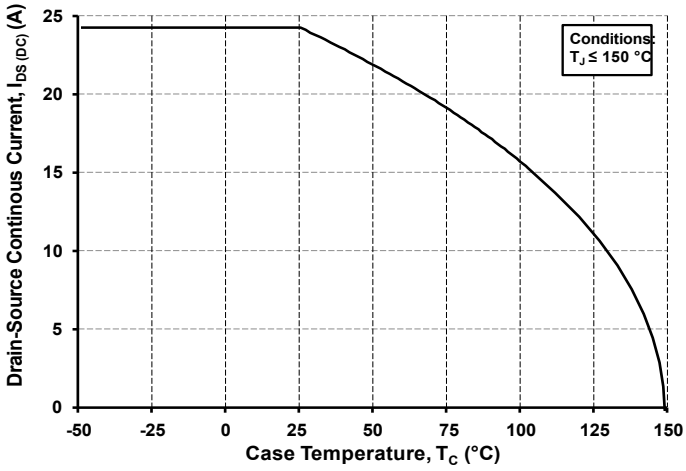


Figure 19. Continuous Drain Current Derating vs. Case Temperature

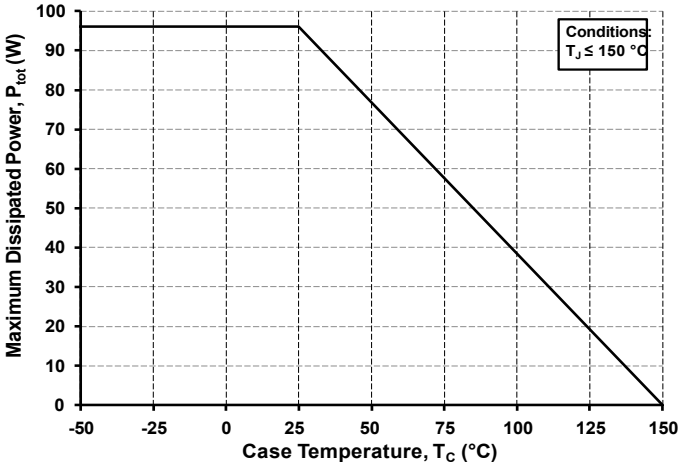


Figure 20. Maximum Power Dissipation Derating vs. Case Temperature

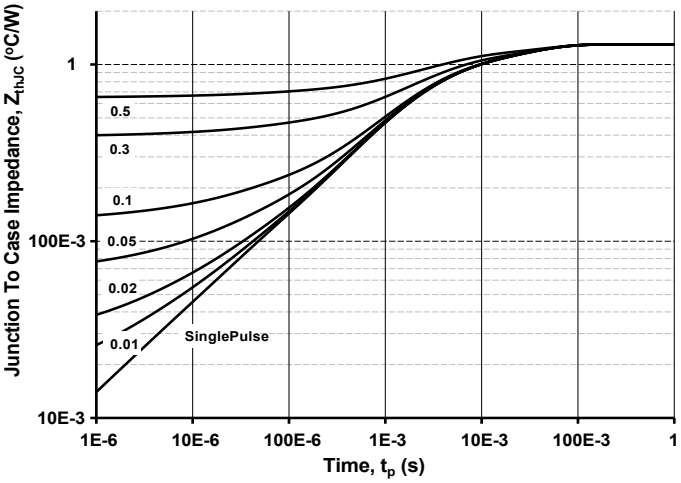


Figure 21. Transient Thermal Impedance (Junction - Case)

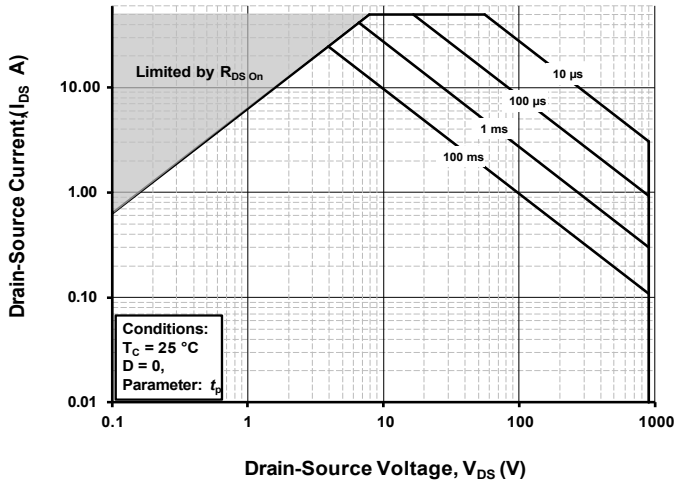


Figure 22. Safe Operating Area

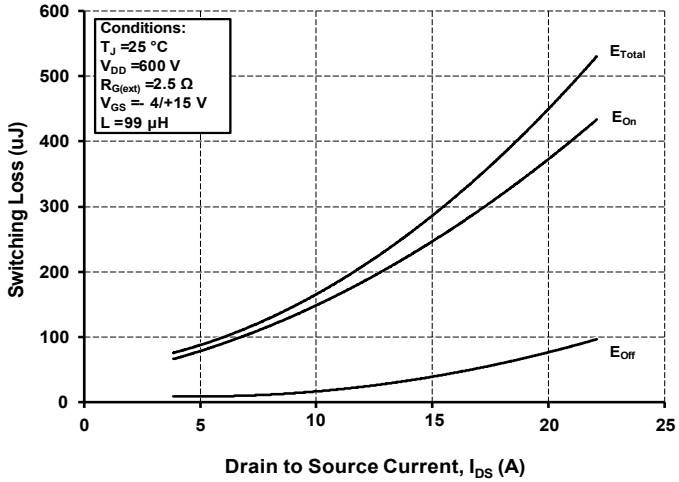


Figure 23. Clamped Inductive Switching Energy vs. Drain Current (V_{DD} = 600V)

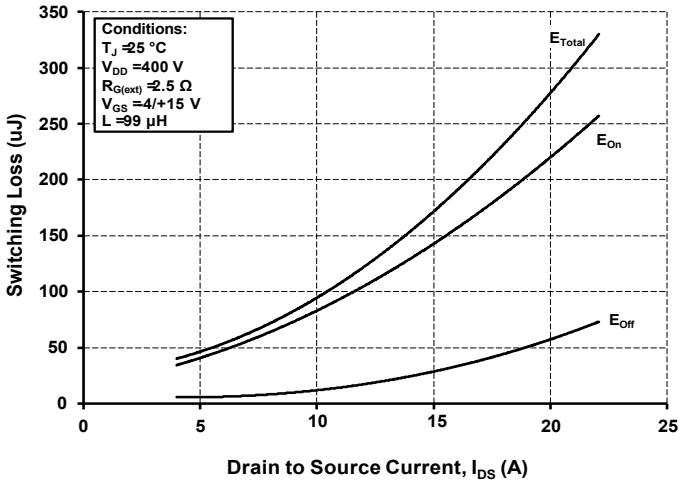


Figure 24. Clamped Inductive Switching Energy vs. Drain Current (V_{DD} = 400V)

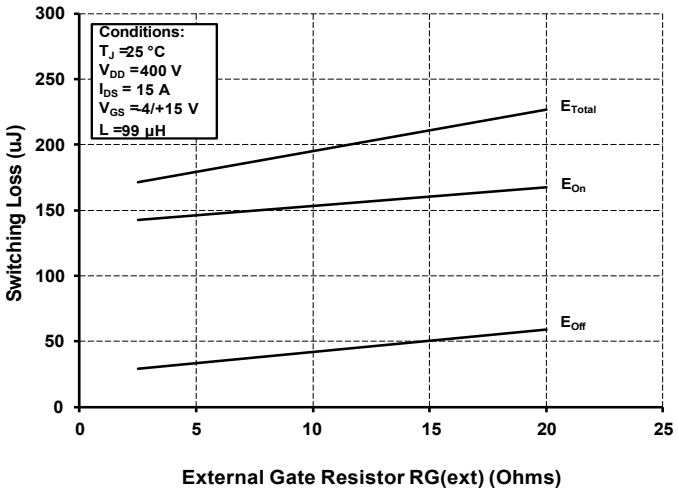


Figure 25. Clamped Inductive Switching Energy vs. $R_{G(ext)}$

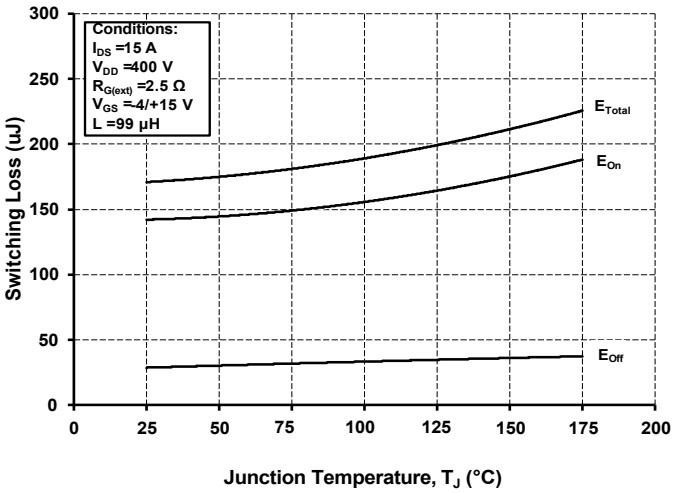


Figure 26. Clamped Inductive Switching Energy vs. Temperature

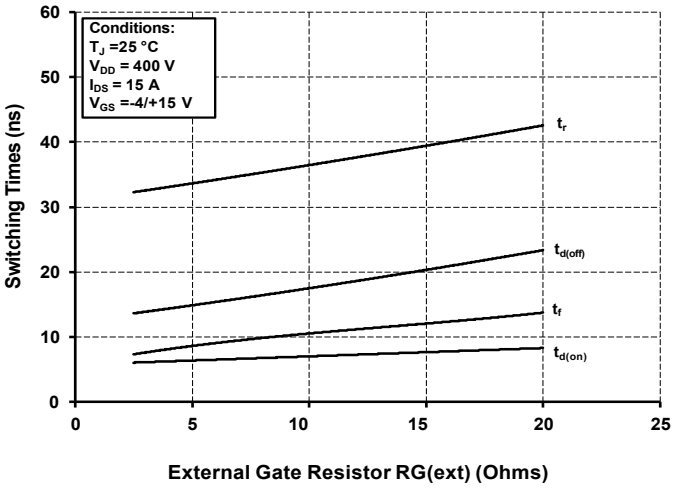


Figure 27. Switching Times vs. $R_{G(ext)}$

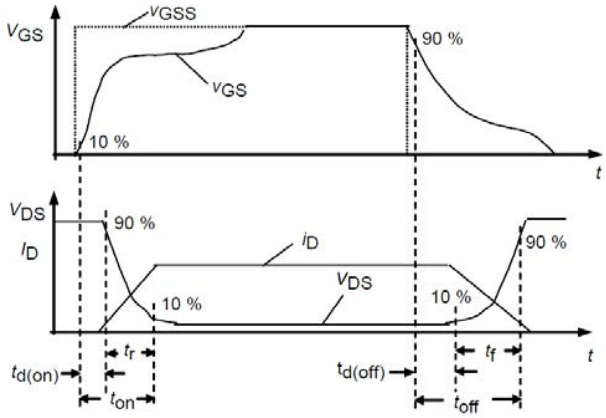
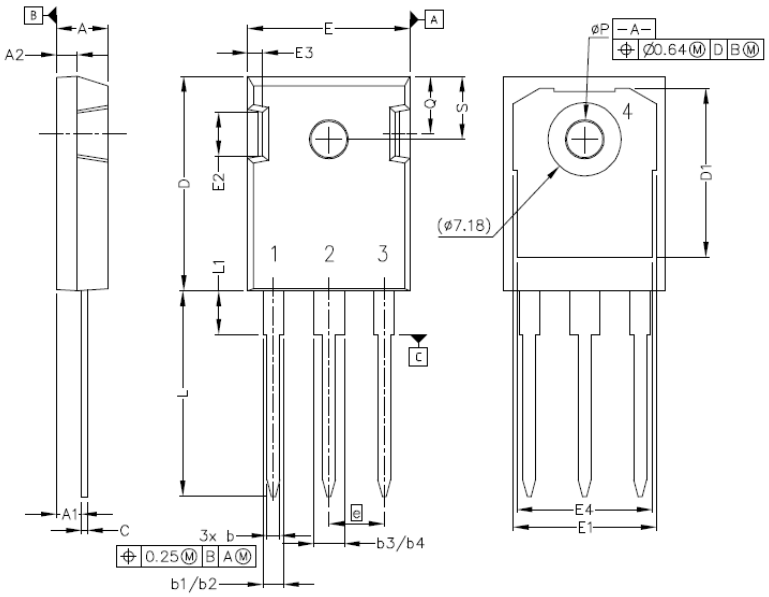
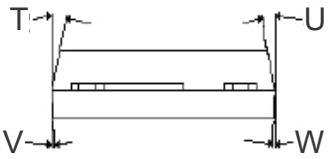


Figure 28. Switching Times Definition

Package Dimensions

Package TO-247



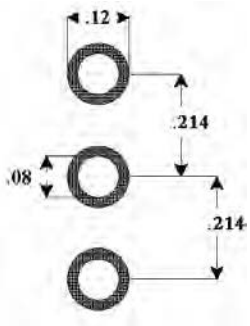


Pinout Information:

- Pin 1 = Gate
- Pin 2, 4 = Drain
- Pin 3 = Source

POS	Inches		Millimeters	
	Min	Max	Min	Max
A	.190	.205	4.83	5.21
A1	.090	.100	2.29	2.54
A2	.075	.085	1.91	2.16
b	.042	.052	1.07	1.33
b1	.075	.095	1.91	2.41
b2	.075	.085	1.91	2.16
b3	.113	.133	2.87	3.38
b4	.113	.123	2.87	3.13
c	.022	.027	0.55	0.68
D	.819	.831	20.80	21.10
D1	.640	.695	16.25	17.65
D2	.037	.049	0.95	1.25
E	.620	.635	15.75	16.13
E1	.516	.557	13.10	14.15
E2	.145	.201	3.68	5.10
E3	.039	.075	1.00	1.90
E4	.487	.529	12.38	13.43
e	.214 BSC		5.44 BSC	
N	3		3	
L	.780	.800	19.81	20.32
L1	.161	.173	4.10	4.40
ØP	.138	.144	3.51	3.65
Q	.216	.236	5.49	6.00
S	.238	.248	6.04	6.30
T	9°	11°	9°	11°
U	9°	11°	9°	11°
V	2°	8°	2°	8°
W	2°	8°	2°	8°

Recommended Solder Pad Layout



TO-247

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